Product Reliability Report

For

RT9728B

Richtek Technology Corporation

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HTOL Test Report

Purpose

The purpose of this specification is to demonstrate the quality or reliability of device RT9728B subjects to the specified conditions over an extended time period and determines this device is capable of passing the specified stress tests to meet Richtek quality criteria.

Scope

The test report is applicable for qualification products of RT9728B.

Product Information

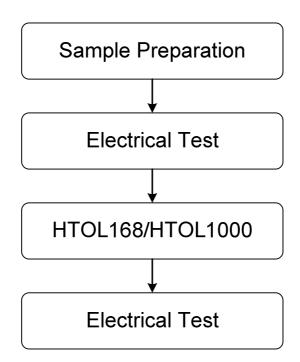
- Part No : RT9728B
- Date Code : CCF2Z
- Package Type : SOT-23-6

Test Items and Conditions

High Temperature Operation Life Test (HTOL)

- Reference Standard : JESD22-A108
- Test Condition $: T_a=125^{\circ}C, V_{IN}=6.5V$
- Test Time : 1000 hours
- Sample Size : 77 ea

Test Flow



www.richtek.com PQA017-01-4

Test Result

| Test | Test | Sample | Fail | Failure Rate (λ) | Failure Rate (λ) |
|------|----------|--------|------|----------------------------|----------------------------|
| Item | Time | Size | ган | FITs, CL 60% | FITs, CL 90% |
| HTOL | 1000 hrs | 77 | 0 | 14.14 | 35.54 |

FIT and MTTF

Test condition: $T_a=125^{\circ}C$, $V_{IN}=6.5V$ Field application temperature (T_{field}): $50^{\circ}C$ Field application voltage (V_{field}): $V_{IN}=5.5V$

 $\begin{aligned} \mathsf{AF}_\mathsf{T} &= \exp[(\mathsf{Ea}/\mathsf{K})^*(1/\mathsf{T}_{\mathsf{field}^-}1/\mathsf{T}_{\mathsf{stress}})] \\ &= 113.89 \; (\mathsf{Ea} \; \mathsf{is} \; \mathsf{conservative} \; \mathsf{value}) \\ \mathsf{AF}_\mathsf{V} &= \exp[\mathsf{C}^*(\mathsf{V}_{\mathsf{stress}} - \mathsf{V}_{\mathsf{field}})] = 7.39 \end{aligned}$

 $AF = AF_T * AF_V = 841.51$

Failure Rate (λ)

 $= [\chi^2 / (2 N^* D^* A)]^* 10^9 \text{ FITs}$

= 35.54 FITs at 90% confidence level

= 14.14 FITs at 60% confidence level

MTTF= $1/\lambda$ = 2.81^{*}10⁷ hours= 3,208 years (at 90% confidence level) MTTF= $1/\lambda$ = 7.07^{*}10⁷ hours= 8,071 years (at 60% confidence level)

- AF = Acceleration Factor
- Ea = Activation Energy (eV)
- K = Boltzman's Constant (8.62 $\times 10^{-5}$ eV/K)
- T = Temperature (%)

V = Voltage (V)

- T_{field} = Temperature Field Conditions
- T_{stress} = Temperature Stress Conditions
- C = Constant of Voltage Acceleration Factor
- V_{field} = Voltage Field Conditions
- V_{stress} = Voltage Stress Conditions
- X² = Chi-square Distribution Function
- N = Sample Size
- D = Device Hours

HTOL Summary

The test results can be applied to all of the products that include RT9728B.

ESD Test Report

Purpose

The ESD tests are used to classify the electrostatic discharge of microcircuits.

Scope

The test report is applicable for qualification products of RT9728B.

Product Information

- Part No : RT9728B
- Date Code : CCF2Z
- Package Type : SOT-23-6

Test Items and Conditions

- Reference Standard : JESD22-A114 (HBM)
 - : JESD22-A115 (MM)
 - : JESD22-C101 (CDM)
- Sample Size : 3ea/voltage
- Failure Criteria : All test samples must pass both diode I-V and function test.
 - Diode I-V Test Criteria

| Criteria | Pass | Fail (Leak) | Fail (Short) | |
|----------------------|-----------------------|----------------------|--------------------|--|
| I-V behavior | $\Delta / rof < 200/$ | AV/rof > 200/ | No diode curve | |
| $\Delta Vref$ at 1uA | $\Delta Vref < 30\%$ | $\Delta Vref > 30\%$ | (I-V turns linear) | |

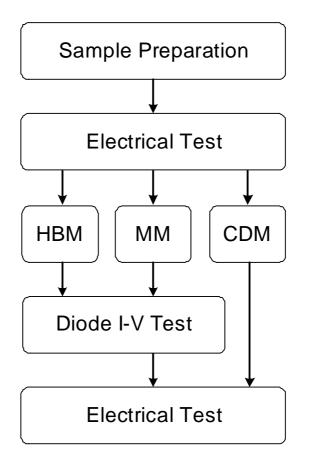
Classification Criteria

| Classification | Class 0 | Class 1 | | | Class 2 | Class 3 | |
|----------------|---------|---------|-------|--------|---------|---------|-----------------|
| Classification | | А | В | С | C1255 Z | A | В |
| | < 250V | 250V~ | 500V~ | 1000V~ | 2000V~ | 4000~ | <u>, 0000\/</u> |
| HBM | | 500V | 1000V | 2000V | 4000V | 8000V | >8000V |

| Classification | Class A | Class B | Class C |
|----------------|---------|------------|---------|
| MM | < 200V | 200V~ 400V | > 400V |

| Classification | Class I | Class II | Class III | Class IV |
|----------------|---------|------------|-------------|----------|
| CDM | < 200V | 200V~ 500V | 500V~ 1000V | >=1000V |

Test Flow



Test Results

HBM: 4000 V MM: 200 V

CDM: 2000 V

ESD Summary

- Classification: HBM: Class 2 MM: Class B CDM: Class IV
- The test results can be applied to all of the products that include RT9728B.

Latch-up Test Report

Purpose

The latch-up test is used to check IC latch-up characteristics.

Scope

The test report is applicable for qualification products of RT9728B.

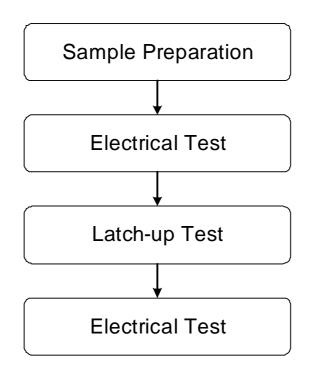
Product Information

- Part No : RT9728B
- Date Code : CCF2Z
- Package Type : SOT-23-6

Test Items and Conditions

| • | Reference Standard | : JESD78D |
|---|--------------------|---------------------------------------------------------------------|
| • | Test Conditions | :±100mA current trigger |
| | | 1.5 X max. Vsupply or MSV whichever is less |
| • | Sample Size | : 9 ea |
| • | Failure Criteria | : If absolute Inom is \leq 25 mA, absolute Inom +10mA is applied. |
| | | : If absolute Inom is > 25mA, > 1.4 X absolute Inom is applied. |

Test Flow



Test Result

| Test Type | Test Pins | Sample Size | Pass/Fail Result | Failure Criteria |
|-----------------------------|-----------------------------------|----------------|---------------------|--------------------------------------------------|
| (+) IT | EN(/EN) /FAULT ILIM VOUT | 3 | Pass | |
| (-) IT | EN(/EN) /FAULT ILIM VOUT | 3 | Pass | 1.4 X Inom or Inom +10mA whichever is greater |
| Vsupply Overvoltage Test | VIN | 3 | Pass | |

Latch-up Summary

- The test results can be applied to all of the products that include RT9728B.
- Any questions or inquiries for regarding related products or service of Richtek, you may contact us through our technical support center. (http://www.richtek.com/contact10.1.jsp)